Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	825	29/603.11,603.13-603.16,603.18. ccls.	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:19
L4	5300	427/127,128.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:19
L5	594	451/4,51.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:19
L6	4792	360/121,122,126,317.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:20
L7	0	(shield$3 adj layer) same (gap adj layer) same magnetoresist	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:21
L8	61	1 and ((shield$3 adj layer) same (gap adj layer) same magnetoresist$3)	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:21
L9	543	(core adj layer) same (insulat$3 adj layer)	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:22
L10	23	(core adj layer) same (insulat$3 adj layer) same planariz$3	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:38
L11	1	8 and 10	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:22
L12	15	("5535079" | "5555147" | "5622525" | "5649351" | "5661620" | "5722156" | "5749769" | "5809636" | "5885131" | "6034848" | "6113464" | "6226149" | "6261468" | "6317288" | "6333841").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/02/10 08:25
L13	18	6 and 10	US-PGPUB; USPAT; USOCR	OR	ON	2005/02/10 08:30
L14	0	13 and @ad<"19990113"	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:35
L15	2	("6757133").PN.	USPAT; USOCR; JPO; DERWENT	OR	OFF	2005/02/10 08:30

L16	13	("5486968" | "5691867" | "5701221" | "5751522" | "5835313" | "5896254" | "6134080" | "6163436" | "6191918" | "6198597" | "6285532" | "6317288" | "6524491").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/02/10 08:30
L17	14	10 and (expos$3 same (core adj layer))	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:34
L18	0	17 and @ad<"19990113"	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:34
L19	1	10 and @ad<"19990113"	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:36
L20	98	expos$3 same planariz$3 same core	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:38
L21	0	5 and 20	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:37
L22	1	1 and 20	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:37
L23	5	6 and 20	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:37
L24	1	(core adj layer) same (insulat$3 adj layer) same planariz$3	JPO	OR	ON	2005/02/10 08:38
L25	1	expos$3 same planariz$3 same core	JPO	OR	ON	2005/02/10 08:40
L26	4	planariz$3 same core same insulat$3	JPO	OR	ON	2005/02/10 08:40
L27	904	expos$3 same core same insulat$3	JPO	OR	ON	2005/02/10 08:41
L28	1	27 and planariz$3	JPO	OR	ON	2005/02/10 08:48
L29	747	27 and @ad<"19990113"	JPO	OR	ON	2005/02/10 08:48
L30	100	29 and (magnetic adj head)	JPO	OR	ON	2005/02/10 08:42
L31	40	30 and (etch$3 or polish$3)	JPO	OR	ON	2005/02/10 08:42
L32	980	sato-kiyoshi.in.	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:47
L33	24	32 and (expos$3 same core same insulat$3)	USPAT; JPO; DERWENT	OR	ON	2005/02/10 08:48
L34	0	33 and planariz$3	JPO	OR	ON	2005/02/10 08:48
L35	0	33 and @ad<"19990113"	JPO	OR	ON	2005/02/10 08:48

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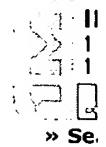
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1 **Floating thin film head fabricated by ion etching method**
Nakanishi, T.; Kogure, K.; Toshima, T.; Yanagisawa, K.;
Magnetics, IEEE Transactions on , Volume: 16 , Issue: 5 , Sep 1980
Pages:785 - 787

[Abstract]   [PDF Full-Text (456 KB)]   **IEEE JNL**

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